

TEST REPORT

Applicant: CHAMPION PERMANENT MAKEUP

Address: Sevastopolska 58/5

Manufacturer: Hangzhou Solong Technology Co., Ltd

Address: Hangzhou Zhejiang CN

EUT: Tattoo Machine

Trade Mark: CHAMPION PERMANENT MAKEUP

Model Number: A1, A2, A3

Date of Receipt: Mar. 31, 2025

Test Date: Mar. 31, 2025 – Apr. 08, 2025

Date of Report: Apr. 08, 2025

Prepared By: Shenzhen Qiqing Technology Co., Ltd.

Address: Room.802, Zhongcheng Sci-tech Building, No.543, Jinbi Road, Biling Street, Pingshan

District, Shenzhen, Guangdong, China

Applicable EN IEC 55014-1:2021 Standards: EN IEC 55014-2:2021

Test Result: Pass

Report Number: QQT202504018ER

Prepared (Engineer): Kelly Tang

Reviewer (Supervisor): Hony Zhou

Approved (Manager): Wendy Chen

This test report is based on a single evaluation of one sample of above mentioned products. It is not permitted to be duplicated in extracts without written approval of Shenzhen Qiqing Technology Co., Ltd.

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VERSION

• 1	Version No.	din ^O Date	Description	
7	00	Apr. 08, 2025	Original	0
	0	in On.	0	ing
	185th	105th	105th	105th

TEST SUMMARY

Ζ.	1EST SUMMARY								
Etino		EMC Emission							
Olding Testing	Standard Test Item		Limit	Result	Remark				
Ojce	Ö.	Conducted Emission at power ports	O,	N/A	7.				
	EN 55014-1	Conducted Emission at load terminals		N/A					
	100	Disturbance power Emission		(est N/A					
Qiqin ⁶	s oic	Radiated Emission below 1GHz	Class B	PASS	didin				
	EN 61000-3-2	Harmonic Current Emission		N/A NOTE (2)	G.				
Esting	EN 61000-3-3	Voltage Fluctuations & Flicker	ting	N/A xin	3				
	EMC Immunity								
	Section EN 55014-2	Test Item	Performance Criteria	Result	Remark				
esting	EN 61000-4-2	Electrostatic Discharge	Billing	PASS	sting				
Qiding Testing	EN 61000-4-3	RF electromagnetic field	A	PASS	19				
Ojoli,	EN 61000-4-4	Fast transients	Oj _{QJ} ,	N/A ci ^{lol}					
	EN 61000-4-5	Surges		N/A					
× (EN 61000-4-6	Injected Current		N/A	49				
Paling	EN 61000-4-11	Volt. Interruptions Volt. Dips		N/A	ding !				

NOTE:

Olding Testing

- (1)" N/A" denotes test is not applicable in this Test Report
- (2) The power consumption of EUT is less than 75W and no Limits apply.

 (3) Voltage dip: 70% reduction Performance Consumption of EUT is less than 75W and no Limits apply.

Voltage Interruptions: 30% reduction - Performance Criteria C

(4) Test Facility: Shenzhen Qiqing Technology Co., Ltd.

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GENERAL INFORMATION

3.1 Description of Device (EUT)

Tattoo Machine EUT:

CHAMPION PERMANENT MAKEUP Trade Mark:

Model Number: A1, A2, A3

Test Model:

Model difference: All models just model name is different

DC 3V Power Supply:

Work Frequency: Below 15MHz

3.2 Tested System Details

None.

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3.3 Block Diagram of Test Set-up

EUT

Test Mode Description

On Mode Mode1.

3.5 Test Auxiliary Equipment

None.

Oiding 73.6 **Test Uncertainty**

±2.56dB Conducted Emission Uncertainty

Oiding Testing Radiated Emission Uncertainty ±3.24dB

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TEST INSTRUMENT USED

For Conducted and Disturbance power Emission Test (843 Shielded Room)

	•		\ •			
Equipment	Manufacturer	Model	Serial	Last Cal.	Next Cal.	
843 Shielded Room	_ Chengyu		843	Jan. 08, 2025	Jan. 07, 2026	
EMI Receiver	R&S	ESR	101421	Jan. 08, 2025	Jan. 07, 2026	
LISN	R&S	ENV216	102417	Jan. 08, 2025	Jan. 07, 2026	
Clamp	COM-POWER	CLA-050	431071	Jan. 08, 2025	Jan. 07, 2026	
3-Loop Antenna	DAZE	ZN30401	13021	Jan. 08, 2025	Jan. 07, 2026	
ISN T8	Schwarzbeck	NTFM 8158	101135	Jan. 08, 2025	Jan. 07, 2026	
ISN T5	Schwarzbeck	NTFM 8158	101136	Jan. 08, 2025	Jan. 07, 2026	
843 Cable 1#	ChengYu	CE Cable	001	Jan. 08, 2025	Jan. 07, 2026	
843 Cable 1#	ChengYu	CE Cable	0020	Jan. 08, 2025	Jan. 07, 2026	

For Radiated Emission Test (966 chamber)

Equipment	Manufacturer	Model	Serial	Last Cal.	Next Cal.	
966 Chamber	ChengYu	966 Room	966	Jan. 08, 2025	Jan. 07, 2026	
Spectrum Analyzer	Agilent	E4408B	MY50140780	Jan. 08, 2025	Jan. 07, 2026	
EMI Receiver	R&S	ESRP7	101393	Jan. 08, 2025	Jan. 07, 2026	
Amplifier	Schwarzbeck	BBV9743B	00153	Jan. 08, 2025	Jan. 07, 2026	
Amplifier	EMEC	EM01G8GA	00270	Jan. 08, 2025	Jan. 07, 2026	
Broadband Trilog Antenna	Schwarzbeck	VULB9162	00306	Jan. 08, 2025	Jan. 07, 2026	
Horn Antenna	Schwarzbeck	BBHA9120D	02139	Jan. 08, 2025	Jan. 07, 2026	
966 Cable 1#	ChengYu	966	004	Jan. 08, 2025	Jan. 07, 2026	
966 Cable 2#	ChengYu 💍	966	003	Jan. 08, 2025	Jan. 07, 2026	

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For Harmonic & Flicker Test (EMS --- site)

For Harmonic & FI	icker Test (EMS	site)	en.	en:	
Equipment Manufacturer		Model	Serial	Last Cal.	Next Cal.
Harmonics, Flicker & power Analyser	LAPLACE INSTRUMENTS	AC2000A	311370	Jan. 08, 2025	Jan. 07, 2026
AC Power Supply	MToni	HPF5010	633659	Jan. 08, 2025	Jan. 07, 2026

For Electrostatic Discharge Immunity Test (EMS --- site)

Ó,	Equipment	Manufacturer	Model	Serial	Last Cal.	Next Cal.
	ESD Tester	SCHLODER	SESD 230	17352	Jan. 08, 2025	Jan. 07, 2026

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For RF Field Strength Susceptibility Test (Keyway --- site)

10.3				10.2	10.3	
Equipment Manuf		Manufacturer	Model	Serial	Last Cal.	Next Cal.
Signal G	Senerator	ON HP	8648A	3625U00573	Jan. 08, 2025	Jan. 07, 2026
Amp	olifier	A&R	500A100	17034	Jan. 08, 2025	Jan. 07, 2026
Amp	olifier	A&R	100W/1000M1	17028	Jan. 08, 2025	Jan. 07, 2026
	Analyzer ~1GHz)	Panasonic	2023B	202301/428	Jan. 08, 2025	Jan. 07, 2026
	oic Field obe	A&R	FP2000	16755	Jan. 08, 2025	Jan. 07, 2026
Ante	enna	EMCO	3108	9507-2534	Jan. 08, 2025	Jan. 07, 2026
Log-periodic A8		A&R	AT1080	16812	Jan. 08, 2025	Jan. 07, 2026

For EFT /B, Surge, Voltage Dips Interruptions Test (EMS --- site)

Equipment	Manufacturer	Model	Serial	Last Cal.	Next Cal.
Transient Comprehensive Immunity Test System	Graphtec	HVIP16T+HCO MPACT 5	192501+192202	Jan. 08, 2025	Jan. 07, 2026
Coupling Clamp	HTEC	001	0001	Jan. 08, 2025	Jan. 07, 2026

For Injected Currents Susceptibility Test (EMS --- site)

Equipment	Manufacturer	Model	Serial	Last Cal.	Next Cal.
C/S Test System	LIONCEL	RIS-6091-85	0191101	Jan. 08, 2025	Jan. 07, 2026
CDN (65	LIONCEL	CDN-M2-16	0191001	Jan. 08, 2025	Jan. 07, 2026
CDN	LIONCEL	CDN-M3-16	0191002	Jan. 08, 2025	Jan. 07, 2026
Injection Clamp	Frankonia O	EMCL-20	18101728-0108	Jan. 08, 2025	Jan. 07, 2026

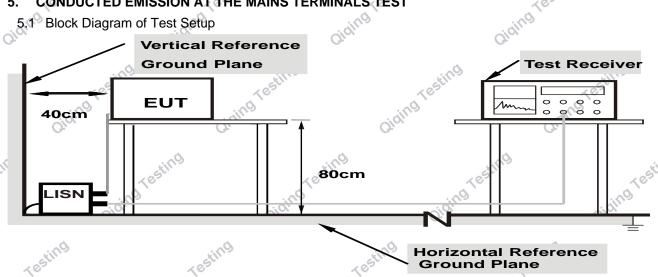
	injection Clamp	Flalikulla	EIVICE-20	10101720-0100	Jan. 00, 202	25 Jan. 01, 2020
105t	Other	Testing	Testing		Testing	
Qiqin ^Q	Na	me	Manufacture	er Mo	odel	Software version
Oje,	EMC Conduction	n Test System	FALA	EZ_	EMC	EMC-CON 3A1.1
	EMC radiation	test system	FALA	EZ_	EMC	FA-03A2
	RF test	system	MAIWEI	MTS	8310	2.0.0.0
	RF communicat	on test system	MAIWEI	MTS	8200	2.0.0.0
	44.					

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CONDUCTED EMISSION AT THE MAINS TERMINALS TEST



Note: 1.Support units were connected to second LISN.

2.Both of LISNs (AMN) are 80 cm from EUT and at least 80 cm from other units and other metal planes

5.2 Test Standard and Limit

EN 55014-1

10	76,		10	76,	Z (2)			
		Limits dB(μV)						
ino	Frequency MHz	At mains terminals		At load terminals and additional terminals				
Oiding Testing		Quasi-peak	Average	Quasi-peak	Average			
Piding		Level	Level	Level	Level			
Ġi.	0.15~0.50	66 ~ 56*	59 ~ 46*	80 💍	70			
	0.50~5.00	56	46		64,0			
	5.00~30.00	60	50	25 th 74	64			

Notes: 1. *Decreasing linearly with logarithm of frequency.

2. The lower limit shall apply at the transition frequencies.

5.3 EUT Configuration on Test

The following equipment's are installed on conducted emission test to meet EN 55014-1 requirement and operating in a manner which tends to maximize its emission characteristics in a 5.4 Operating Condition of EUT
5.4.1 Setup normal application.

- 5.4.1 Setup the EUT and simulators as shown in Section 5.1.
- 5.4.2 Turn on the power of all equipment.
- 5.4.3 Let the EUT work in test modes and test it.

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5.5 Test Procedure

The EUT is put on the ground and connected to the AC mains through a Artificial Mains Network (AMN). This provided a 50ohm coupling impedance for the tested equipments. Both sides of AC line are checked to find out the maximum conducted emission levels according to the **EN 55014-1** regulations during conducted emission test.

The bandwidth of the test receiver (R&S Test Receiver ESR) is set at 10KHz.

The frequency ranges from 150kHz to 30MHz is investigated.

5.6 Test Result

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The EUT is powered by DC, no requirements for this item.

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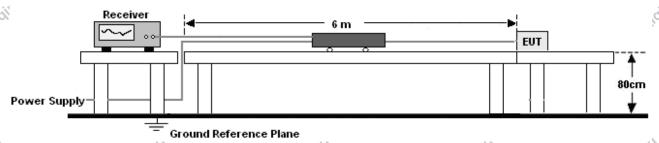
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6. DISTURBANCE POWER EMISSION TEST

6.1 Block Diagram of Test Setup



6.2 Test Standard and Limit

EN 55014-1

Frequency	Limits dB(pW)				
MHz	Quasi-peak Level	Average Level			
30-300	45-55 AIR [®]	35-45 _{sin} 9			

Notes: The limit Increasing linearly with the frequency from 30 to 300MHz.

Margin when performing disturbance power Measurement in the frequency range 30 MHz to 300 MHz

Frequency	Margin Quasi-peak dB(pW)		
MHz	Household and similar appliances / Tools		
200 to 300	0 to 10		

Note: The limit Increasing linearly with the frequency from 200 to 300MHz.

6.3 EUT Configuration on Test

The following equipment's are installed on conducted emission test to meet EN 55014-1 requirement and operating in a manner which tends to maximize its emission characteristics in a normal application.

6.4 Operating Condition of EUT

- 6.4.1 Setup the EUT and simulators as shown in Section 6.1.
- 6.4.2 Turn on the power of all equipment.
- 6.4.3 Let the EUT work in test modes and test it.

6.5 Test Procedure

- a. The absorbing clamp was placed around the lead to be measured, with its current transformer towards the equipment under test.
 - b. All connectors having a connected lead shall be terminated in a manner representative of use.
- c. The absorbing clamp was applied successively to all leads whose length is 25cm or longer, unscreened or screened, which may be connected to the individual units of the equipment under test.
- d. The Product was placed on a nonconductive table of 0.8 m of height above the floor and at least 0.8m from other metallic objects and from any person. The lead to be measured shall be stretched in a straight horizontal line for length sufficient to accommodate the absorbing clamp.
 - e. Pre-scans were performed with a quasi-peak detector and an average detector.

c. The scans were performed with a quasi peak detector and an average detector



f. At each test frequency the absorbing clamp shall be moved along the lead until the maximum value is found between a position adjacent to the equipment under test and a distance of about a half wavelength from it.

The bandwidth of the test receiver (R&S Test Receiver ESR) is set at 10KHz.

6.6 Test Result

The product meets the requirements of Section 7, so no testing in this section.

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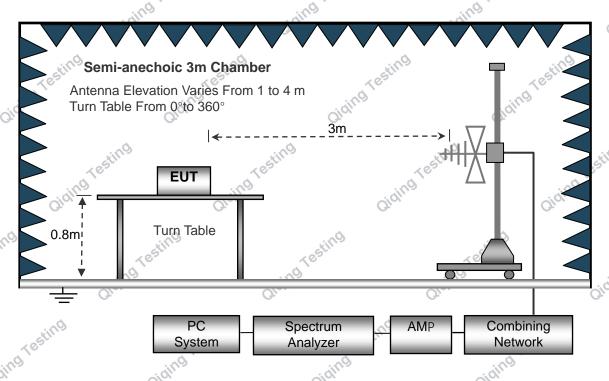
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RADIATION EMISSION TEST

7.1 Block Diagram of Test Setup



7.2 Test Standard and Limit

EN 55014-1

d and Limit 5014-1	ing Testing	ingTesting	ingresting
Frequency	Distance	Field Strengths Limits	
MHz	(Meters)	dB(μV)/m	
30~230	3 254111	40.0	
230~1000	3	47.0	Palin

Remark

- (1) The smaller limit shall apply at the cross point between two frequency bands.
- (2) Distance refers to the distance in meters between the measuring instrument, antenna and the closed point of any part of the device or system.

7.3 EUT Configuration on Test

The EN 55014-1 regulations test method must be used to find the maximum emission during radiated emission test.

The configuration of EUT is the same as used in conducted emission test.

Please refer to Section 2.2.

7.4 Operating Condition of EUT

Same as conducted emission test, which is listed in Section 2.2 except the test set up replaced as Section 4.1.

7.5 Test Procedure

- 1) The radiated emissions test was conducted in a semi-anechoic chamber.
- 2) The tabletop EUT was placed upon a non-metallic table 0.8m above the ground reference plane. And for floor-standing arrangement, the EUT was placed on the horizontal ground reference plane, but

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separated from metallic contact with the ground reference plane by 0.1m of insulation.

- 3) Before final measurements of radiated emissions, a pre-scan was performed in the spectrum mode with the peak detector to find out the maximum emissions spectrum plots of the EUT.
- 4) The frequencies of maximum emission were determined in the final radiated emissions measurement. At each frequency, the EUT was rotated 360°, and the antenna was raised and lowered from 1 to 4 meters in order to determine the maximum disturbance. Measurements were performed for both horizontal and vertical antenna polarization.
 - 5) The bandwidth setting on the field strength meter (R&S Test Receiver ESCI) is set at 120KHz. Oiding Testing

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Olding Testing 6) The frequency range from 30MHz to 1000MHz is checked.

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Olding Testing 7.6 Test Result

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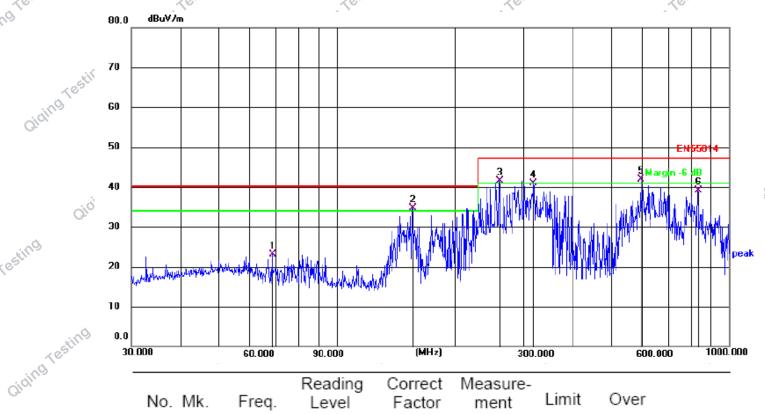
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Ling	ing		-ing	ing			
Radiation Emission Test Data							
Temperature:	24.5 °C	-	Relative Humidity:	54%			
Pressure:	1009hPa	O	Polarization:	Horizontal			
Test Voltage:	DC 3V	Paris	Test Mode:	Mode 1			



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over	
		MHz	dBu∀	dB	dBu∀/m	dB/m	dB	Detector
1		68.6310	40.03	-16.85	23.18	40.00	16.82	QP
2	! 1	55.9101	53.46	-18.79	34.67	40.00	5.33	QP
3	! 2	259.2338	55.19	-13.64	41.55	47.00	5.45	QP
4	3	317.7010	53.18	-12.21	40.97	47.00	6.03	QP
5	* 5	95.1327	48.63	-6.80	41.83	47.00	5.17	QP
6	8	30.4001	41.72	-2.53	39.19	47.00	7.81	QP

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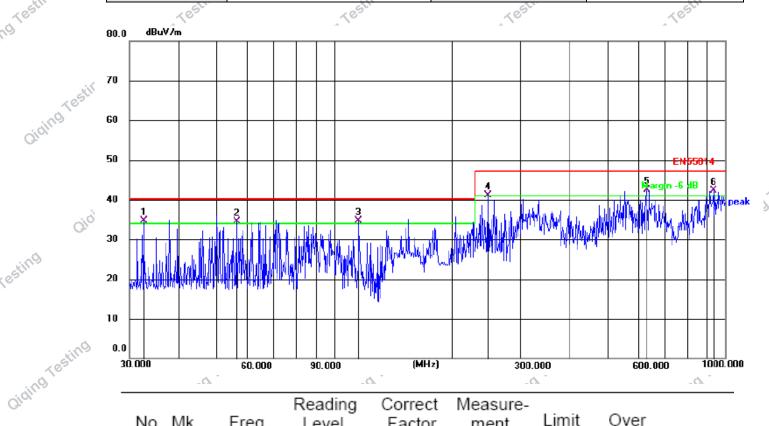
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Radiation Emission Test Data							
Temperature:	24.5 °C	-	Relative Humidity:	54%			
Pressure:	1009hPa	O	Polarization:	Vertical			
Test Voltage:	DC 3V	eni	Test Mode:	Mode 1			



-	No.	Mk	. Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over	
105			MHz	dBu∀	dB	dBu∀/m	dB/m	dB	Detector
Oiding Tee	1	İ	32.6340	50.26	-15.55	34.71	40.00	5.29	QP §
-	2	ļ	56.3948	48.46	-13.86	34.60	40.00	5.40	QP
-	3	ļ	115.7256	52.52	-17.89	34.63	40.00	5.37	QP
Ġ	4	ļ	247.6818	55.16	-13.99	41.17	47.00	5.83	QP
-	5	×	627.2737	48.65	-6.13	42.52	47.00	4.48	QP
-	6	İ	932.2715	43.40	-1.05	42.35	47.00	4.65	QP

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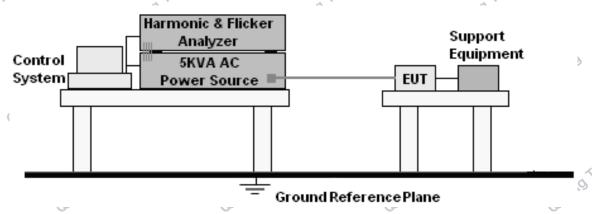
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HARMONIC CURRENT EMISSION TEST

8.1 Block Diagram of Test Setup



3.2 Test Standard

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EN 61000-3-2

Operating Condition of EUT

Setup the EUT as shown in Section 8.1.

Turn on the power of all equipment.

Let the EUT work in test mode and test it.

Test Procedure

Olding Testing The power cord of the EUT is connected to the output of the test system. Turn on the power of the EUT and use the test system to test the harmonic current level.

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Test Results 8.5

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The EUT is powered by DC, no requirements for this item.

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VOLTAGE FLUCTUATIONS & FLICKER TEST

9.1 Block Diagram of Test Setup

Same as Section 8.1.

9.2 Test Standard

EN 61000-3-3

9.3 Operating Condition of EUT

ting Condition of EUT
Same as Section 8.3. The power cord of the EUT is connected to the output of the test system. Turn on the power of the EUT and use the test system to test the harmonic current level.

Flicker Test Limit

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Test items		Limits	
Pst	Qiqi.	1.0 QiQi	Ojoj.
dc	^	3.3%	^
Tmax	IUA	4.0%	sting
dt		Not exceed 3.3% for 50	0ms

Test Procedure

The power cord of the EUT is connected to the output of the test system. Turn on the power of the EUT and use the test system to test the harmonic current level.

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9.5 Test Results

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The EUT is powered by DC, no requirements for this item.

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ening ening 10.IMMUNITY TEST OF GENERAL THE PERFORMANCE CRITERIA

Produ	ct Standard	EN 55014-2				
2101	TERION A	The apparatus shall continue to operate as intended during the test. No degradation of performance or loss of function is allowed below a performance level (or permissible loss of performance) specified by the manufacturer, when the apparatus is used as intended. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and from				
	-iding,	what the user may resonably expect from the apparatus if used as intended				
e ^{ting}	TERION B ^{itting}	The apparatus shall continue to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level (or permissible loss of performance) specified by the manufacturer, when the apparatus is used as intended. During the test, degradation of performance is allowed, however, no change of actual operating state or stored data is allowed. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the				
Oiding Test		allowed. If the minimum performance level or the permissible performance loss				
Qiding Test		allowed. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and from what the user may reasonably				

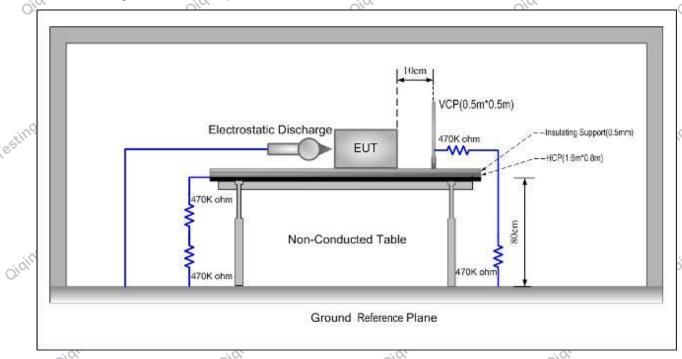
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11.ELECTROSTATIC DISCHARGE IMMUNITY TEST

11.1 Block Diagram of Test Setup



11.2 Test Standard

EN 55014-2, EN 61000-4-2

11.3 Severity Levels and Performance Criterion

Severity Level: 3 / Air Discharge: ±8KV

Level: 2 / Contact Discharge: ±4KV

Performance criterion: B

11.4 Test Procedure

- a. Electrostatic discharges were applied only to those points and surfaces of the Product that are accessible to users during normal operation.
- b. The test was performed with at least ten single discharges on the pre-selected points in the most sensitive polarity.
- c. The time interval between two successive single discharges was at least 1 second.
- d. The ESD generator was held perpendicularly to the surface to which the discharge was applied and the return cable was at least 0.2 meters from the Product.
- e. Contact discharges were applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.
- f. Air discharges were applied with the round discharge tip of the discharge electrode approaching the Product as fast as possible (without causing mechanical damage) to touch the Product. After each discharge, the ESD generator was removed from the Product and re-triggered for a new single discharge. The test was repeated until all discharges were complete.
- g. At least ten single discharges (in the most sensitive polarity) were applied to the Horizontal Coupling Plane at points on each side of the Product. The ESD generator was positioned vertically at a distance of 0.1 meters from the Product with the discharge electrode touching the HCP.
- h. At least ten single discharges (in the most sensitive polarity) were applied to the center of one vertical edge of the Vertical Coupling Plane in sufficiently different positions that the four faces of the

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Product were completely illuminated. The VCP (dimensions 0.5m x 0.5m) was placed vertically to and 0.1 meters from the Product

11.5 Test Results

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Please refer to the following page

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			Electros	static Dis	char	ge Test Data			
	Temperature:		25.1℃ (100°)		Humidity:		55% _{din} o		İ
	Power Supply:		DC 3V		Test Mode:		Mode 1		İ
resting	Discharge	Discharge Position		Voltag	je	Min. No. of Discharge per	Required	D	ding
)	Method			(±kV)		polarity (Each Point)	Level	Result	
			ive Surfaces	4		10	В	Pass	i
10°	Contact	Indirect I	Indirect Discharge HCP		100	10	(B)	Pass	
Oiding Tes	Discharge Indirect		irect Discharge VCP 4		0	10	ding B	Pass	ding
Ō,	All	Slots, Apertures, and Insulating Surfaces		8		10	В	Pass	1
	Note: N/A		Testi		•	105th	. <	Str	

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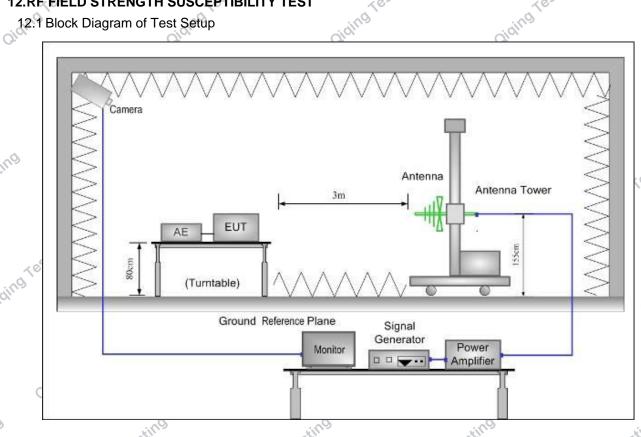
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12.RF FIELD STRENGTH SUSCEPTIBILITY TEST



12.2 Test Standard

EN 55014-2, EN 61000-4-3

12.3 Severity Levels and Performance Criterion

Severity Level 2, 3V / m

Performance criterion: A

12.4 Test Procedure

The EUT and its simulators are placed on a turn table which is 0.8 meter above ground. EUT is set 3 meter away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarization of the antenna are set on test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually.

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All the scanning conditions are as follows:

Condition of Test

Fielded Strength

Radiated Signal

Scanning Frequency

Dwell time of radiated

Waiting Time

Remarks

3 V/m (Severity Level 2)

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Modulated

80 - 1000 MHz

0.0015 decade/s

1 Sec.

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			R/S T	est Data		
Qiding Tes	Temperature:	O O		Humidity:	55% Mode 1	
Qick	Power Supply :			Test Mode:		
	Criterion:	A sting		Steps	1%	sting
G	Frequency (MHz)	Position		Strength F	Required Level	Circlind Result
Testing	80 – 1000	Front, Right, Back, Left	esting	3	of Ating	Pass
	Note: N/A	Ojdi.		O,	dir	Ojdi.
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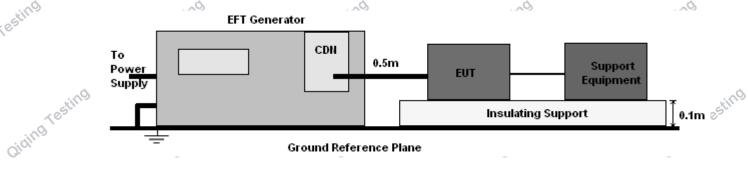
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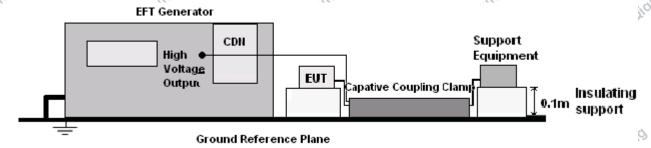
13.ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST

13.1 Block Diagram of EUT Test Setup

For input a.c. / d.c. power port:



For signal lines and control lines:



13.2 Test Standard

EN 55014-2, EN 61000-4-4

13.3 Severity Levels and Performance Criterion

Severity Level 2 at 1KV, Pulse Rise time & Duration: 5 nS / 50 nS

Performance criterion: B

13.4 Test Procedure

EUT shall be placed 0.8m high above the ground reference plane which is a min.1m*1m metallic sheet with 0.65mm minimum thickness. This reference ground plane shall project beyond the EUT by at least 0.1m on all sides and the minimum distance between EUT and all other conductive structure, except the ground plane beneath the EUT, shall be more than 0.5m

For input and output AC power ports:

The EUT is connected to the power mains by using a coupling device which couples the EFT interference signal to AC power lines. Both polarities of the test voltage should be applied during compliance test and the duration of the test is 2 minutes.

13.5 Test Results

The EUT is powered by DC, no requirements for this item.

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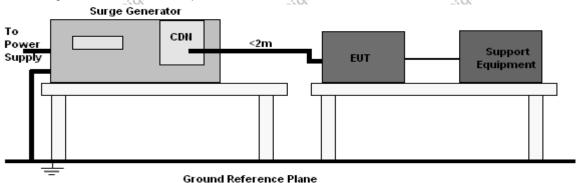
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14.SURGE TEST

14.1 Block Diagram of EUT Test Setup



didinia 14.2 Test Standard

EN 55014-2, EN61000-4-5

14.3 Severity Levels and Performance Criterion

Severity Level: Line to Line, Level 2 at 1KV; Severity Level: Line to Earth, Level 3 at 2KV.

Performance criterion: B

14.4 Test Procedure

- 1) Set up the EUT and test generator as shown on section 11.1
 - 2) For line-to-line coupling mode, provide a 1KV 1.2/50us voltage surge (at open-circuit condition) and 8/20us current surge to EUT selected points.
 - 3) At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are conducted during test.
 - 4) Different phase angles are done individually.
 - 5) Repeat procedure 2) to 4) except the open-circuit test voltage change from 1KV to 2KV for line to earth coupling mode test.
 - 6) Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

14.5 Test Result

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The EUT is powered by DC, no requirements for this item.

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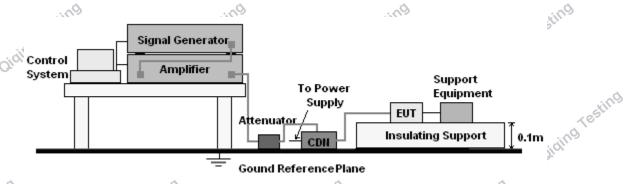
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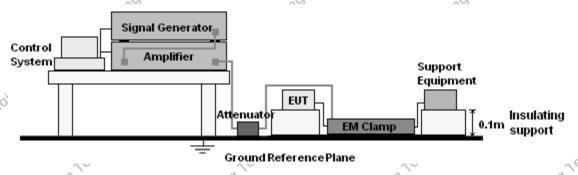
15.INJECTED CURRENTS SUSCEPTIBILITY TEST

15.1 Block Diagram of EUT Test Setup

For input a.c. / d.c. power port:



For signal lines and control lines:



15.2 Test Standard

EN 55014-2, EN61000-4-6

15.3 Severity Levels and Performance Criterion

Severity Level 2: 3V(rms), 150KHz $\,\sim\,$ 80MHz

Performance criterion: A

15.4 Test Procedure

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- 1) Set up the EUT, CDN and test generator as shown on section 12.1
- 2) Let EUT work in test mode and measure.
- 3) The EUT and supporting equipments are placed on an insulating support 0.1m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane at above 0.1-0.3m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
 - 4) The disturbance signal described below is injected to EUT through CDN.
- 5) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 6) The frequency range is swept from 150KHz to 80MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1KHz sine wave
- 7) The rate of sweep shall not exceed 1.5×10⁻³ decades/s. Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.

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8) Recording the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

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15.5 Test Result The EUT is powered by DC, no requirements for this item. Olding Testing Olding Testing Olding Testing Olding Testing nd Testing Olding Testing Olding Testing Olding Testing Oiding Testing Oiding Testing Olding Testing Olding Testing Olding Testing Olding Testing Oiding Test Olding Testing Olding Testing Olding Testing Olding Testing Olding Testing Olding Testing Oiding Testing Olding Testing Oiding Testing Oiding Testing Oiding Testing Olding Testing Oiding Testing Olding Testing Oiding Testing Oiding Testing Oiding Testing Oiding Testing Olding Testing Olding Testing Olding Testing Oiding Testing lding Testing Olding Testing Olding Testing Olding Testing Olding Testing Olding Testing ding Testing Email: Service@qq-lab.com enzhen, Guangdong CL

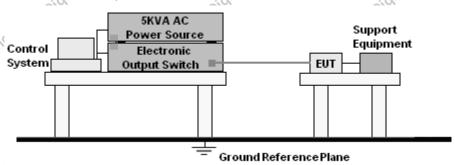
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16.VOLTAGE DIPS AND INTERRUPTIONS TEST

16.1 Block Diagram of EUT Test Setup



16.2 Test Standard

EN 55014-2, EN61000-4-11

16.3 Severity Levels and Performance Criterion Input and Output AC Power Ports.

✓ Voltage Dips.

✓ Voltage Interruptions.

10°	100	100	100
Environmental Phenomena	Test Specification	Test Specification Units	
Testing	100 0.5	% Reduction period	С
Voltage Dips	0iding 60	% Reduction period	C diging
resting.	30 25	% Reduction period	Cesting C

Oidina 16.4 Test Procedure

- 1) Set up the EUT and test generator as shown on section 14.1
- 2) The interruption is introduced at selected phase angles with specified duration. There is a 3mins minimum interval between each test event.
- 3) After each test a full functional check is performed before the next test.
- 4) Repeat procedures 2 & 3 for voltage dips, only the level and duration is changed.
- 5) Record any degradation of performance.

16.5 Test Result

The EUT is powered by DC, no requirements for this item.

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Figure 1 Overall view

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Figure 2 Overall view Oiding Testing

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Figure 5 Internal view

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Figure 7 Internal view



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